

Description :

CD4011 is a low-power, wide range working voltage 2-input NAND gate integrated circuit designed using CMOS technology. It integrates four independent 2-input NAND gate circuits internally, with high anti-interference and driving capabilities.

Features :

- Low input current: $I_{IN} \leq 1\mu A$, @ $V_{IN}=V_{DD}=15V$, $T_a=25$
- Low static power consumption: $I_{DD} \leq 6\mu A$, @ $V_{DD}=15V$, $T_a=25$ °C
- Wide operating voltage range: 3.0Vto15.0V
- Encapsulation form: DIP14, SOP14

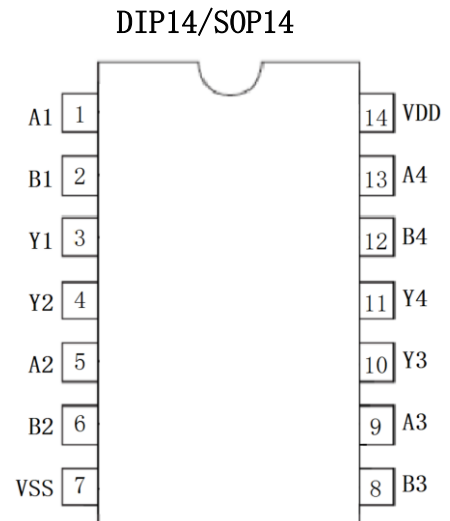
Application:

- Digital Logic Driven
- Industrial control applications

- Wireless doorbell
- Other application areas

Pin Assignment:

PIN NO.	Definition	PIN NO.	Definition
DIP14/SOP14		DIP14/SOP14	
1	A1	14	VDD
2	B1	13	B4
3	Y1	12	A4
4	Y2	11	Y4
5	A2	10	Y3
6	B2	9	B3
7	VSS	8	A3

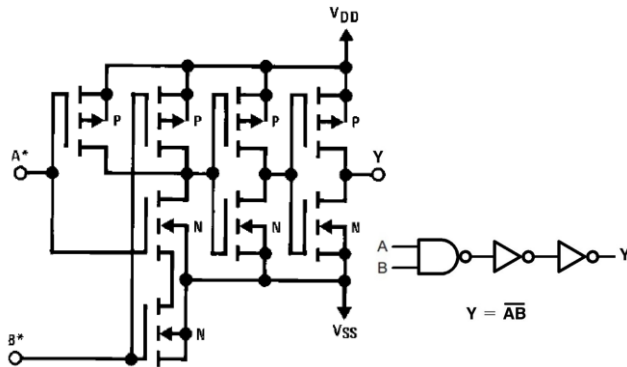


Absolute Maximum Ratings:

parameter	Symbol	Max	Unit
working voltage	V_{CC}	-0.5-20	V
Input/output voltage	$V_{IN}, V_{I/O}$	-0.5+VSS-VDD+0.5V	V
Dissipated power	P_D	500	mW
working temperature	T_A	0-70	°C
Storage temperature	T_S	-65-150	°C
Pin welding temperature	T_W	260,10s	°C

Note: Limit parameters refer to the limit values that cannot be exceeded under any conditions. If the limit value is exceeded, it may cause physical damage such as product degradation; At the same time, it cannot be guaranteed that the chip can function properly when approaching the limit parameters.

logic diagram



Truth table

Inputs		Output
A	B	Y
L	L	H
L	H	H
H	L	H
H	H	L

H = High Logic Level

L = Low Logic Level

Recommended operating conditions

parameter	Symbol	Min	Typ	Max	Unit
working voltage	V_{DD}	2.5		15	V
Input and output voltage	$V_{IN}, V_{I/O}$	0		V_{DD}	V
working temperature	T_A	0		60	°C

electrical characteristic

DC electrical characteristics: ($T_a=25$)

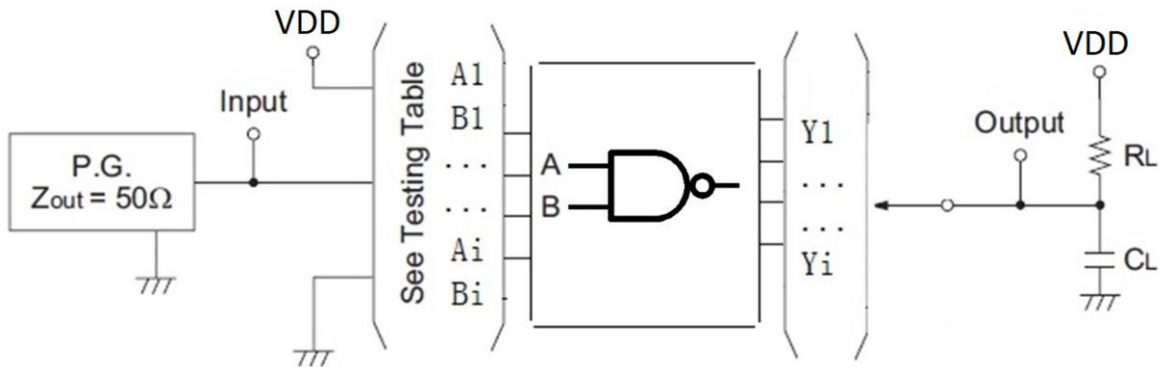
symbol	parameter	Test conditions	V_{DD} (V)	min	typ	max	unit
V_{IH}	High level effective input voltage	$ I_O \leq 1\mu A$	$V_O = 0.5V$	5	3.5		V
			$V_O = 1V$	10	7.0		V
			$V_O = 1.5V$	15	11.0		V
V_{IL}	Low level effective input voltage	$ I_O \leq 1\mu A$	$V_O = 4.5V$	5		1.5	V
			$V_O = 9V$	10		3.0	V
			$V_O = 13.5V$	15		4.0	V
V_{OH}	high level output voltage	$ I_{OUT} < 1\mu A$	5	4.95			V
			10	9.95			V
			15	14.95			V
V_{OL}	Low Level Output Voltage	$ I_{OUT} < 1\mu A$	5			0.05	V
			10			0.05	V
			15			0.05	V
I_{IN}	Input Current	$V_{IN} = V_{DD}$ or V_{SS}	15		0.01	1.0	μA
I_{OH}	High Level Output Current		$V_O = 4.6V$	5	-1.0	-0.5	mA
			$V_O = 9.5V$	10	-2.1	-1.3	mA
			$V_O = 13.5V$	15	-8.0	-3.4	mA
I_{OL}	Low Level Output Current		$V_O = 0.4V$	5	0.5	2.2	mA
			$V_O = 0.5V$	10	1.3	5.1	mA
			$V_O = 1.5V$	15	3.4	19	mA
I_{DD}	Working current	$V_{IN} = V_{DD}$ or V_{SS}	5		0.1	4	μA
			10		0.1	5	μA
			15		0.1	6	μA

AC electrical characteristics: Ta=25 °C, RL=200k, CL=47pF, see test method.

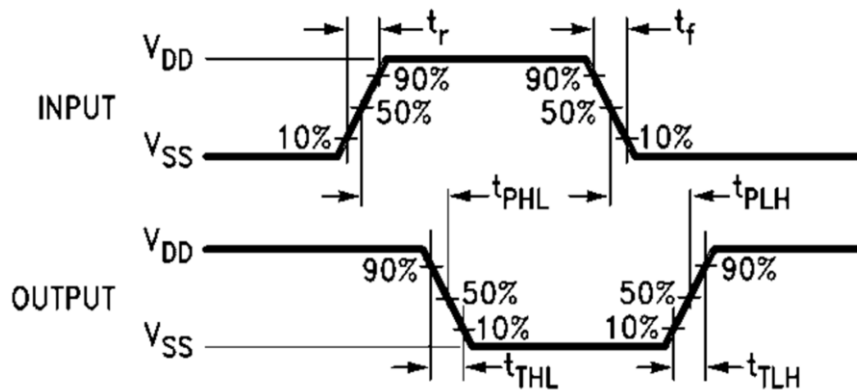
parameter	symbol	Test conditions	min	typ	max	unit
最大传输延迟时间 A、B to Y	t _{PHL}	VDD=5V		62		ns
	t _{PLH}			55		ns
	t _{PHL}	VDD=10V		35		ns
	t _{PLH}			35		ns
	t _{PHL}	VDD=15V		30		ns
	t _{PLH}			28		ns

test method

1. Test wiring diagram



2. Schematic diagram of waveform measurement

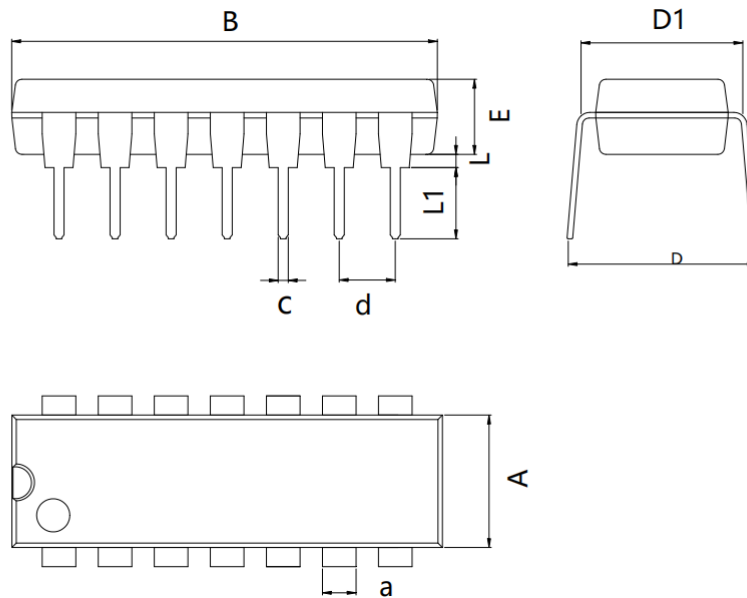


Note:

1. See Testing Table refers to the corresponding testing items in the A C electrical characteristics table;
2. The CL capacitor is an external patch capacitor (0603), connected near the output pin, and the capacitor ground is close to the chip VSS;
3. Input: Port input level, f=1MHz, D=50% square wave, tr=tf ≤ 20ns;
4. Output: Y-end output test.

PACKAGE MECHANICAL DATA

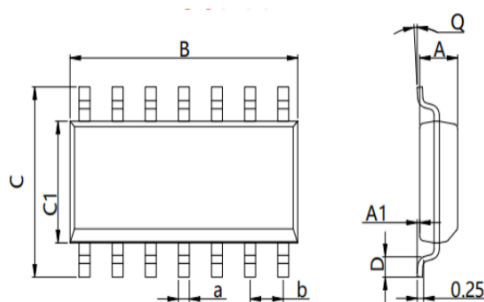
DIP14



Dimensions In Millimeters (DIP14)

Symbol:	A	B	D	D1	E	L	L1	a	C	d
Min:	6.10	18.94	8.40	7.42	3.10	0.50	3.00	1.50	0.40	2.54 BSC
Max:	6.68	19.56	9.00	7.82	3.55	0.70	3.60	1.55	0.50	

SOP14



Dimensions In Millimeters (SOP14)

Symbol:	A	A1	B	C	C1	D	Q	a	b
Min:	1.35	0.05	8.55	5.80	3.80	0.40	0°	0.35	1.27 BSC
Max:	1.55	0.20	8.75	6.20	4.00	0.80	8°	0.45	